



Test Floor Ops

Designed for test floors performing wafer sort or final test operations, Test Floor Ops can be integrated into a manufacturing or engineering environment where time-sensitive response is critical, including OSATs and IDMs, Foundries and Fabless companies. It provides real-time views of the testers, as well as automatic detection of equipment or process-related issues and provides a wide selection of operational reports such as equipment utilization.

- *A complementary solution to the Optimal+ Semiconductor Operations Platform*
- *Requires Global Ops and works in conjunction with other Optimal+ solutions*

Highlights

- Generates extreme efficiency and superior quality results for semiconductor production & engineering floors
- Identifies equipment problems and failures as they arise
- Automates test equipment pause/shutdown before problems become costly
- Drives real-time rules for myriad process control functions
- Manufactures intelligence from time-sensitive test processes, including wafer sort and final test

Test Floor Ops, Real-Time Results

Test Floor Ops (TFO) takes decision making on the test floor a step beyond, offering production and engineering facilities a complete, self-contained solution for manufacturing intelligence in-the-moment from every station. The feature-rich solution is integrated into the heart of your operations, gauging the performance of your processes, equipment and test programs in real-time and triggering corrective measures as necessary.

Activating automated rules in real-time on every tester for key equipment functions, it enables semiconductor companies to detect a tester malfunction on a given wafer as early as the fifth or sixth die and can trigger an automatic pause or shutdown if necessary. Test Floor Ops acts upon insights derived from data generated on all production floor equipment for maximizing bottom-line metrics, from yield to productivity and quality.

Test Floor Ops Solution

How It Works

1



ANALYZE DATA

Powerful analysis tools help engineering teams and operational decision makers alike to scrutinize their data and detect the issues and potential red flags across their global supply chain

2



CREATE RULES

Establish automated operational monitors pertaining to every facet of manufacturing that enable you to automatically catch problems as they occur

3



SIMULATE SCENARIOS

Run a newly-created rule against actual historical test data in order to ascertain that the problem it targets can actually be identified; amend the rule as necessary if it doesn't achieve the desired outcome

4



PUBLISH TO SUPPLY CHAIN

Once a rule is green-lighted for achieving its intended goal, it can be propagated to the entire tester fleet

5



ACT ON TIME

When the rule is triggered based on the collected data, various actions can be taken, from manufacturing disposition (wafer hold/retest and more) through email notifications to product engineering or subcons to taking real time actions (such as pausing the tester)

6



VALIDATE RULES

Once a rule is verified as running smoothly and the supply chain adapts to the new requirements, it can be further "tightened" to continuously achieve even more improvement over time